

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination PANEK ET AL.	
		Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

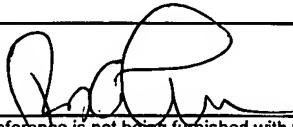
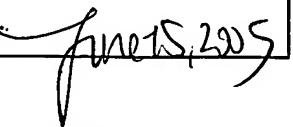
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,439,628 A	08-1995	Huang, Hwang-Wen	264/175
	B	US-5,254,617 A	10-1993	Inoue et al.	524/433
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 56-005842 A	01-1981	Japan	Nakazawa et al.	C08L 23/12
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	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	JP 56-005842 (English abstract)		
	V			
	W			
	X			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.